

Знание языков

Հայերեն English Русский Українська

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Analytics for AI Related Applications of Multidimensional Multitape Finite Automata

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Electronics, Communications and Networks 2023 49-60

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Functional Safety Compliant Test & Repair Framework for System-on-Chip Lifecycle Management

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Polynomial algorithm for equivalence problem of deterministic multitape finite automata

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Memory Physical Aware Multi-Level Fault Diagnosis Flow

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Securing Test Infrastructure of System-on-Chips

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Armenia: Communicating to World Community in Electronic Test and Design

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Testing Electronic Memories Based on Fault and Test Algorithm Periodicity

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